

AMENDMENTS TO THE SPECIFICATION

Please replace the paragraph of page 1, lines 33 through page 2, line 1 of the originally-filed Specification with the following amended paragraph:

The international patent application no. WO 92/18053, relates to a method of testing an implant attached to a bone of a human or animal subject. The method comprises the steps of bringing a member into contact with the implant; detecting at least one resonance frequency of the member when it is in contact with the implant; and interpreting the detected resonance frequency in terms of the degree of attachment of the implant with respect to the bone. However, the method implies using an analysinganalyzing unit being in contact with the implant through a wire.

Please replace the paragraph of page 3, lines 19-25 of the originally-filed Specification with the following amended paragraph:

According to most preferred embodiment, the detectable part comprises a magnetic member. Thus, the detector comprises a coil. The arrangement further comprises an amplifier, a processor, and a data store. The signals detected by the detector are amplified by the amplifier and applied as an input to be analysedanalyzed. The analysedanalyzed output, which represents a ratio of a response voltage to the excitation, is fed to the processor, which varies the frequency output of the oscillator of the analyseranalyzer, and stores the results in the data store.

Please replace the paragraph of page 5, lines 12-17 of the originally-filed Specification with the following amended paragraph:

Signals detected by the probe 151 are amplified by an amplifier 154 and applied as an input to the analyseranalyzer. The output from the analyseranalyzer, which represents the ratio of the response voltage to the excitation, is fed to a processor such as a microprocessor 155, which is used to vary the frequency output of the oscillator of the analyseranalyzer, and store the results in a data store 156. The results can be printed out, and/or displayed on a display or the like.

Please replace the paragraph of page 5, line 27 through page 6, line 6 of the originally-filed Specification with the following amended paragraph:

The light source on the tip of the probe illuminates the beam and the light detector 253b detects the reflected light. The detected light signal is converted to an electrical signal by the detector, and signals detected by the probe 251 are amplified by an amplifier 254 and applied as an input to the analyser analyzer. The output from the analyser analyzer, which represents the ratio of the response voltage to the excitation, is fed to a processor such as a microprocessor 255, which is used to vary the frequency output of the oscillator of the analyser analyzer, and store the results in a data store 256. The results can be printed out, and/or displayed on a display or the like.

Please replace the paragraph of page 7, lines 11-14 of the originally-filed Specification with the following amended paragraph:

The testing apparatus 550 includes the probe 551 and the response analyzer unit 552. The probe can be part of the magnetic field generator. The probe 550 comprises a coil 553 for detecting interferences in the magnetic field 565. The analysing analyzing can be conducted as described in conjunction with the ~~first~~ first embodiment.